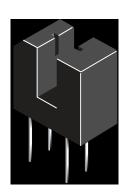
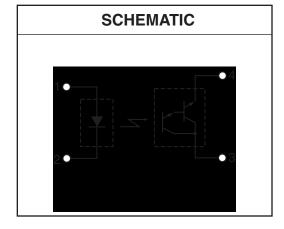


H22B1 **H22B2 H22B3**

PACKAGE DIMENSIONS NOTES:



- 1. Dimensions for all drawings are in inches (mm).
- 2. Tolerance of \pm .010 (.25) on all non-nominal dimensions unless otherwise specified.



DESCRIPTION

The H22B1, H22B2 and H22B3 consist of a gallium arsenide infrared emitting diode coupled with a silicon photodarlington in a plastic housing. The packaging system is designed to optimize the mechanical resolution, coupling efficiency, ambient light rejection, cost and reliability. The gap in the housing provides a means of interrupting the signal with an opaque material, switching the output from an "ON" to an "OFF" state.

FEATURES

- Opaque housing
- Low cost
- .035" apertures
- High I_{C(ON)}



H22B1 H22B2 H22B3

ABSOLUTE MAXIMUM RATINGS (T _A = 25°C unless otherwise specified)								
Parameter	Symbol	Rating	Unit					
Operating Temperature	T _{OPR}	-55 to +100	°C					
Storage Temperature	T _{STG}	-55 to +100	°C					
Soldering Temperature (Iron) ^(2,3 and 4)	T _{SOL-I}	240 for 5 sec	°C					
Soldering Temperature (Flow) ^(2 and 3)	T _{SOL-F}	260 for 10 sec	°C					
INPUT (EMITTER)								
Continuous Forward Current	I _F	50	mA					
Reverse Voltage	V _R	6	V					
Power Dissipation ⁽¹⁾	P _D	100	mW					
OUTPUT (SENSOR)								
Collector to Emitter Voltage	V _{CEO}	30	V					
Emitter to Collector Voltage	V _{ECO}	6	V					
Collector Current	I _C	40	mA					
Power Dissipation (T _C = 25°C) ⁽¹⁾	P _D	150	mW					

NOTES:

- 1. Derate power dissipation linearly 1.67 mW/°C above 25°C.
- 2. RMA flux is recommended.
- 3. Methanol or isopropyl alcohols are recommended as cleaning agents.
- 4. Soldering iron 1/16" (1.6 mm) minimum from housing.



H22B1

H22B2

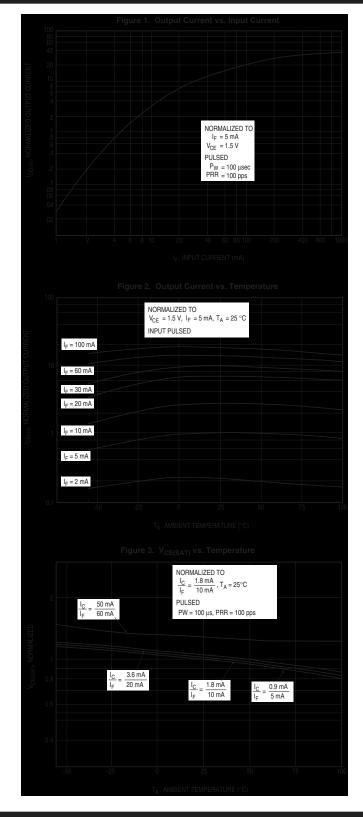
H22B3

PARAMETER	TEST CONDITIONS	SYMBOL	DEVICES	MIN	TYP	MAX	UNITS
INPUT (EMITTER)							
Forward Voltage	I _F = 60 mA	V _F	All	_	_	1.7	V
Reverse Breakdown Voltage	I _R = 10 μA	V _R	All	6.0	_	_	V
Reverse Leakage Current	V _R = 3 V	I _R	All	_	_	1.0	μA
OUTPUT (SENSOR)							
Emitter to Collector Breakdown	$I_F = 100 \mu A, E_e = 0$	BV _{ECO}	All	7.0	_	_	V
Collector to Emitter Breakdown	$I_C = 1 \text{ mA}, E_e = 0$	BV _{CEO}	All	30	_	_	V
Collector to Emitter Leakage	$V_{CE} = 25 \text{ V}, E_e = 0$	I _{CEO}	All	_	_	100	nA
COUPLED On-State Collector Current	I _F = 2 mA, V _{CE} = 1.5 V		H22B1	0.5	_	_	mA
			H22B2	1.0	_	_	
			H22B3	2.0	_	_	
	I _F = 5 mA, V _{CE} = 1.5 V		H22B1	2.5	_	_	
		I _{C(ON)}	H22B2	5.0	_	_	
			H22B3	10	_	_	
	I _F = 10 mA, V _{CE} = 1.5 V		H22B1	7.5	_	_	
			H22B2	14	_	_	
			H22B3	25	_	_	
Saturation Voltage	I _F = 10 mA, I _C = 1.8 mA		All	_	_	1.0	V
	I _F = 60 mA, I _C = 50 mA	V _{CE(SAT)}	H22B1/2	_	_	1.5	V
Turn-On Time	$I_F = 10 \text{ mA}, V_{CC} = 5 \text{ V},$ $R_L = 750\Omega$		All	_	45	_	μs
	$I_F = 60 \text{ mA}, V_{CC} = 5 \text{ V},$ $R_L = 75\Omega$	t _{on}	All	_	7	_	
Turn-Off Time	$I_F = 10 \text{ mA}, V_{CC} = 5 \text{ V},$ $R_L = 750\Omega$		All	_	250	_	- µs
	$I_F = 60 \text{ mA}, V_{CC} = 5 \text{ V},$ $R_L = 75\Omega$	t _{off}	All	_	45	_	

H22B1

H22B2

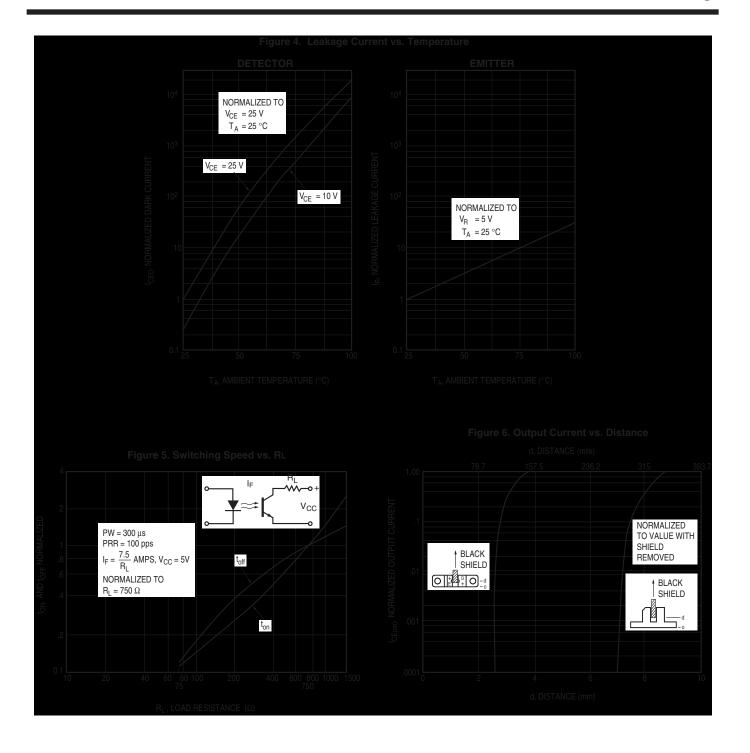
H22B3



H22B1

H22B2

H22B3





H22B1

H22B2

H22B3

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